Analysis and Design of Complex Embedded Systems

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Message from the Guest Editors

Dear Colleagues,

Modern embedded systems are becoming increasingly complex because of their use of various integrated components, technologies, and functionalities. The complexity of these hardware and software systems requires new appropriate processes, tools, and methodologies for analysis, design, and validation purposes. Maintaining the overall competitiveness of the design process with regard to cost and time-to-market constraints remains, of course, a key concern.

In addition, these increasingly connected and complex systems also must face cyberattacks, which often cause serious dysfunctions and undermine the security of such systems. The relationships between security and safety are thus at the heart of the current concerns of specialists in the field of complex embedded systems. However, on the other hand, a safety constraint such as the introduction of redundant components or diagnostic ports can increase the attack surface of the system. The complexity of software and hardware components used in embedded systems has thus motivated the adoption of new approaches to anticipate security and safety problems.

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Special Issue

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Message from the Editor-in-Chief

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